



RELIABILITY REPORT
FOR
MAX14753EUE+
PLASTIC ENCAPSULATED DEVICES

February 27, 2009

MAXIM INTEGRATED PRODUCTS

120 SAN GABRIEL DR.
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Approved by
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Conclusion

The MAX14753EUE+ successfully meets the quality and reliability standards required of all Maxim products. In addition, Maxim's continuous reliability monitoring program ensures that all outgoing product will continue to meet Maxim's quality and reliability standards.

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I. Device Description

A. General

The MAX14752/MAX14753 are 8-to-1 and dual 4-to-1 high-voltage analog multiplexers. Both devices feature 60 (typ) on-resistance with 0.03 (typ) on-resistance flatness. These low on-resistance multiplexers conduct equally well in either direction. Flexible logic levels for the channel-select interface are defined by the EN input. The MAX14752 is a 8-to-1 multiplexer and MAX14753 is a dual 4-to-1 multiplexer. Both devices operate with dual supplies of $\pm 10\text{V}$ to $\pm 36\text{V}$, or a single supply of $+20\text{V}$ to $+72\text{V}$. The MAX14752/MAX14753 are available in a 16-pin TSSOP package and are pin compatible with the industry-standard DG408/DG409. Both the MAX14752/MAX14753 are specified over the extended -40°C to $+85^{\circ}\text{C}$ operating temperature range.



II. Manufacturing Information

A. Description/Function:	8-Channel/Dual 4-Channel 72V Analog Mux
B. Process:	BCD8
C. Number of Device Transistors:	813
D. Fabrication Location:	Oregon
E. Assembly Location:	ATP Philippines, Carsem Malaysia, UTL Thailand
F. Date of Initial Production:	July 26, 2008

III. Packaging Information

A. Package Type:	16-pin TSSOP B. Lead
Frame:	Copper
C. Lead Finish:	100% matte Tin
D. Die Attach:	
E. Bondwire:	(mil dia.)
F. Mold Material:	Epoxy with silica filler
G. Assembly Diagram:	#
H. Flammability Rating:	Class UL94-V0
I. Classification of Moisture Sensitivity per JEDEC standard J-STD-020-C	Level 1
J. Single Layer Theta Ja:	106°C/W
K. Single Layer Theta Jc:	27°C/W
L. Multi Layer Theta Ja:	90°C/W
M. Multi Layer Theta Jc:	27°C/W

IV. Die Information

A. Dimensions:	86 X 99 mils
B. Passivation:	Si ₃ N ₄ /SiO ₂ (Silicon nitride/ Silicon dioxide)
C. Interconnect:	Aluminum/Si (Si = 1%)
D. Backside Metallization:	None
E. Minimum Metal Width:	3.0 microns (as drawn)
F. Minimum Metal Spacing:	3.0 microns (as drawn)
G. Bondpad Dimensions:	5 mil. Sq.
H. Isolation Dielectric:	SiO ₂
I. Die Separation Method:	Wafer Saw



V. Quality Assurance Information

- | | |
|-----------------------------------|---|
| A. Quality Assurance Contacts: | Ken Wendel (Director, Reliability Engineering)
Bryan Preeshl (Managing Director of QA) |
| B. Outgoing Inspection Level: | 0.1% for all electrical parameters guaranteed by the Datasheet.
0.1% For all Visual Defects. |
| C. Observed Outgoing Defect Rate: | < 50 ppm |
| D. Sampling Plan: | Mil-Std-105D |

VI. Reliability Evaluation

A. Accelerated Life Test

The results of the 135°C biased (static) life test are shown in Table 1. Using these results, the Failure Rate (λ) is calculated as follows:

$$\lambda = \frac{1}{\text{MTTF}} = \frac{1.83}{192 \times 4340 \times 48 \times 2} \quad (\text{Chi square value for MTTF upper limit})$$

(where 4340 = Temperature Acceleration factor assuming an activation energy of 0.8eV)

$$\lambda = 22.4 \times 10^{-9}$$
$$\lambda = 22.4 \text{ F.I.T. (60\% confidence level @ 25°C)}$$

The following failure rate represents data collected from Maxim's reliability monitor program. Maxim performs quarterly 1000 hour life test monitors on its processes. This data is published in the Product Reliability Report found at <http://www.maxim-ic.com/>. Current monitor data for the BCD8 Process results in a FIT Rate of 2.3 @ 25C and 39.6 @ 55C (0.8 eV, 60% UCL)

B. Moisture Resistance Tests

The industry standard 85°C/85%RH or HAST testing is monitored per device process once a quarter.

C. E.S.D. and Latch-Up Testing

The AJ54-1 die type has been found to have all pins able to withstand a HBM transient pulse of +/-2000 V per JEDEC JESD22-A114-D. Latch-Up testing has shown that this device withstands a current of +/-250 mA, 1.5x VCCMax Overvoltage per JESD78.



Table 1
Reliability Evaluation Test Results

MAX14753EUE+

TEST ITEM	TEST CONDITION	FAILURE IDENTIFICATION	SAMPLE SIZE	NUMBER OF FAILURES
Static Life Test (Note 1)	Ta = 135°C Biased Time = 192 hrs.	DC Parameters & functionality	48	0
Moisture Testing (Note 2) 85/85	Ta = 85°C RH = 85% Biased Time = 1000hrs.	DC Parameters & functionality	77	0
Mechanical Stress (Note 2) Temperature Cycle	-65°C/150°C 1000 Cycles Method 1010	DC Parameters & functionality	77	0

Note 1: Life Test Data may represent plastic DIP qualification lots.

Note 2: Generic Package/Process data